Author index

Ahmed, M.F., see Ashour, A.	89 (1995) 159	Al2O3 interface using the MCs+-SIMS	
Alnot, M., see Lobstein, N.	89 (1995) 307	technique	89 (1995) 169
Anandan, C., X-ray photoelectron spectro-		Cheng, P., see Xue, G.	89 (1995) 77
scopic study of room-temperature evolu-		Choi, JG., see Lee, H.J.	89 (1995) 121
tion of oxide-covered hydrogenated		Chopra, K.L., see Rao, M.V.H.	89 (1995) 417
amorphous silicon/aluminium interface	89 (1995) 57	Collaud-Coen, M., see Gröning, P.	89 (1995) 83
Arai, M., Y. Nishiyama, T. Masuda and K.		Colling, C.W., see Lee, H.J.	89 (1995) 121
Hashimoto, The distribution of activa-			
tion energy for hydrogen desorption over		Demanet, C.M., Atomic force microscopy	
silica-supported nickel catalysts deter-		determination of the topography of fly-	
mined from temperature-programmed		ash particles	89 (1995) 97
desorption spectra	89 (1995) 11	Dietler, G., see Gröning, P.	89 (1995) 83
Ashour, A., M.R. Ebeid, N. El-Kadry, M.F.		Ding, J., see Xue, G.	89 (1995) 77
Ahmed and A.A. Ramadan, Thermal ef-		Domínguez, P.S., see Tejedor, P.	89 (1995) 271
fects on structural characterization of		Donaton, R.A., K. Lokere, R. Verbeeck and	
evaporated CdTe films during and after		K. Maex, Etching of CoSi, in HF-based	
deposition	89 (1995) 159	solutions	89 (1995) 221
Ayame, A., see Tomizuka, H.	89 (1995) 281		
rayame, ray ove rominada, ra	07 (1770) 201	Ebeid, M.R., see Ashour, A.	89 (1995) 159
Pai C and Form V	89 (1995) 331	Ehrhardt, J.J., see Lobstein, N.	89 (1995) 307
Bai, C., see Fang, Y.	69 (1993) 331	El-Kadry, N., see Ashour, A.	89 (1995) 159
Bolt, P.H., S.F. Lobner, J.W. Geus and F.H.P.M. Habraken, Interfacial reaction			
		Fang, Y., C. Bai, T. Wang and YQ. Tang,	
of NiO with Al ₂ O ₃ (1120) and polycrys-	00 (1005) 220	Characterization of triplex RNA poly	
talline α-Al ₂ O ₃	89 (1995) 339	[rU] · poly[rA] · poly[rU] adsorbed on	
Bonnet, J., see Lévêque, G.	89 (1995) 211	silver colloids by Fourier transform sur-	
Bram, Ch., see Starke, U.	89 (1995) 175	face enhanced Raman scattering and	
Butman, M.F., J. Nakamura, S. Kamidoi		scanning tunneling microscopy	89 (1995) 331
and H. Kawano, Influence of surface		Figoli, N.S., see L'Argentière, P.C.	89 (1995) 63
charge on thermal positive ion emission	00 (1005) 222		
from potassium bromide	89 (1995) 323	Geus, J.W., see Bolt, P.H.	89 (1995) 339
		Goldmann, A., see Kürpick, U.	89 (1995) 383
Callegaro, L., see Vavassori, P.	89 (1995) 93	Gråsjö, L., G. Hultquist, K.L. Tan and M.	
Cañón, M.G., see L'Argentière, P.C.	89 (1995) 63	Seo, Surface reactions on palladium hy-	
Cerofolini, G.F. and L. Meda, Chemistry at		dride in vacuum, air and water studied	
silicon crystalline surfaces	89 (1995) 351	in situ with mass spectrometry	89 (1995) 21
Cerofolini, G.F., G. La Bruna and L. Meda,		Gröning, P., O.M. Küttel, M. Collaud-Coen,	
Enhanced silicon oxidation in O2 and		G. Dietler and L. Schlapbach, Interac-	
O_2 : F_2	89 (1995) 361	tion of low-energy ions (< 10 eV) with	
Chattopadhyay, P. and S. Sanyal, Capaci-		polymethylmethacrylate during plasma	
tance-voltage characteristics of Schot-		treatment	89 (1995) 83
tky barrier diode in the presence of		Gu, H.C., see Wang, X.K.	89 (1995) 297
deep-level impurities and series resis-		Gunter, P.L.J. and J.W. Niemantsverdriet,	
tance	89 (1995) 205	Thickness determination of uniform	
Chen, X. and Y. Wang, A study of the		overlayers on rough substrates by angle-	
composition distribution at the Ti/		dependent XPS	89 (1995) 69

Author index

Ahmed, M.F., see Ashour, A.	89 (1995) 159	Al2O3 interface using the MCs+-SIMS	
Alnot, M., see Lobstein, N.	89 (1995) 307	technique	89 (1995) 169
Anandan, C., X-ray photoelectron spectro-		Cheng, P., see Xue, G.	89 (1995) 77
scopic study of room-temperature evolu-		Choi, JG., see Lee, H.J.	89 (1995) 121
tion of oxide-covered hydrogenated		Chopra, K.L., see Rao, M.V.H.	89 (1995) 417
amorphous silicon/aluminium interface	89 (1995) 57	Collaud-Coen, M., see Gröning, P.	89 (1995) 83
Arai, M., Y. Nishiyama, T. Masuda and K.		Colling, C.W., see Lee, H.J.	89 (1995) 121
Hashimoto, The distribution of activa-			
tion energy for hydrogen desorption over		Demanet, C.M., Atomic force microscopy	
silica-supported nickel catalysts deter-		determination of the topography of fly-	
mined from temperature-programmed		ash particles	89 (1995) 97
desorption spectra	89 (1995) 11	Dietler, G., see Gröning, P.	89 (1995) 83
Ashour, A., M.R. Ebeid, N. El-Kadry, M.F.		Ding, J., see Xue, G.	89 (1995) 77
Ahmed and A.A. Ramadan, Thermal ef-		Domínguez, P.S., see Tejedor, P.	89 (1995) 271
fects on structural characterization of		Donaton, R.A., K. Lokere, R. Verbeeck and	
evaporated CdTe films during and after		K. Maex, Etching of CoSi, in HF-based	
deposition	89 (1995) 159	solutions	89 (1995) 221
Ayame, A., see Tomizuka, H.	89 (1995) 281		
rayame, ray over romana, ra	07 (1770) 201	Ebeid, M.R., see Ashour, A.	89 (1995) 159
Pai C and Form V	89 (1995) 331	Ehrhardt, J.J., see Lobstein, N.	89 (1995) 307
Bai, C., see Fang, Y.	69 (1993) 331	El-Kadry, N., see Ashour, A.	89 (1995) 159
Bolt, P.H., S.F. Lobner, J.W. Geus and F.H.P.M. Habraken, Interfacial reaction			
		Fang, Y., C. Bai, T. Wang and YQ. Tang,	
of NiO with Al ₂ O ₃ (1120) and polycrys-	00 (1005) 220	Characterization of triplex RNA poly	
talline α-Al ₂ O ₃	89 (1995) 339	[rU] · poly[rA] · poly[rU] adsorbed on	
Bonnet, J., see Lévêque, G.	89 (1995) 211	silver colloids by Fourier transform sur-	
Bram, Ch., see Starke, U.	89 (1995) 175	face enhanced Raman scattering and	
Butman, M.F., J. Nakamura, S. Kamidoi		scanning tunneling microscopy	89 (1995) 331
and H. Kawano, Influence of surface		Figoli, N.S., see L'Argentière, P.C.	89 (1995) 63
charge on thermal positive ion emission	00 (1005) 222		
from potassium bromide	89 (1995) 323	Geus, J.W., see Bolt, P.H.	89 (1995) 339
		Goldmann, A., see Kürpick, U.	89 (1995) 383
Callegaro, L., see Vavassori, P.	89 (1995) 93	Gråsjö, L., G. Hultquist, K.L. Tan and M.	
Cañón, M.G., see L'Argentière, P.C.	89 (1995) 63	Seo, Surface reactions on palladium hy-	
Cerofolini, G.F. and L. Meda, Chemistry at		dride in vacuum, air and water studied	
silicon crystalline surfaces	89 (1995) 351	in situ with mass spectrometry	89 (1995) 21
Cerofolini, G.F., G. La Bruna and L. Meda,		Gröning, P., O.M. Küttel, M. Collaud-Coen,	
Enhanced silicon oxidation in O2 and		G. Dietler and L. Schlapbach, Interac-	
O_2 : F_2	89 (1995) 361	tion of low-energy ions (< 10 eV) with	
Chattopadhyay, P. and S. Sanyal, Capaci-		polymethylmethacrylate during plasma	
tance-voltage characteristics of Schot-		treatment	89 (1995) 83
tky barrier diode in the presence of		Gu, H.C., see Wang, X.K.	89 (1995) 297
deep-level impurities and series resis-		Gunter, P.L.J. and J.W. Niemantsverdriet,	
tance	89 (1995) 205	Thickness determination of uniform	
Chen, X. and Y. Wang, A study of the		overlayers on rough substrates by angle-	
composition distribution at the Ti/		dependent XPS	89 (1995) 69

Habraken, F.H.P.M., see Bolt, P.H.	89 (1995) 339	L'Argentière, P.C., M.G. Cañón and N.S.	
Hachimi, A., see Lobstein, N.	89 (1995) 307	Figoli, XPS studies of the effect of Mn	89 (1995) 63
Hadj Zoubir, N. and M. Vergnat, Thermal		on Pd/Al ₂ O ₃	89 (1995) 63
desorption spectroscopy study of chemi-	89 (1995) 35	Lee, H.J., JG. Choi, C.W. Colling, M.S.	
cally etched porous silicon Hammer, C.F., see Ye, X.R.	89 (1995) 151	Mudholkar and L.T. Thompson, Tem- perature-programmed desorption and de-	
Hammer, L., see Starke, U.	89 (1995) 175		
Hanebuchi, M., T. Katoh and K. Morita,	89 (1993) 173	composition of NH ₃ over molybdenum nitride films	89 (1995) 121
Characterization of thin Ag films de-		Lee, W.Y., see Hong, J.K.	89 (1995) 229
posited onto InP(001)-p(2 × 4) surface		Lévêque, G. and J. Bonnet, Quantitative correction of backscattering in Auger	
at room temperature by means of LEED, RHEED, AES and RBS-channeling		electron spectroscopy of thin films	89 (1995) 211
techniques	89 (1995) 113	Li, Y.S., see Wong, P.C.	89 (1995) 255
Haneman, D., see Wu, S.	89 (1995) 289	Li, Y.S., P.C. Wong and K.A.R. Mitchell,	09 (1993) 233
Hartner, W., see Starke, U.	89 (1995) 175	XPS investigations of the interactions of	
Hashimoto, K., see Arai, M.	89 (1995) 11	hydrogen with thin films of zirconium	
Hautojärvi, P., see Vaara, T.	89 (1995) 103	oxide. II. Effects of heating a 26 Å thick	
		film after treatment with a hydrogen	
Heinz, K., see Starke, U.	89 (1995) 175	plasma	89 (1995) 263
Hong, J.K., IH. Oh, SA. Hong and W.Y.			89 (1995) 203
Lee, The effect of anodic polarization		Linares-Solano, A., see Muñoz-Guillena,	89 (1995) 197
on a Ag electrode deposited on YSZ	90 (1005) 220	M.J.	
solid electrolyte	89 (1995) 229	Lobner, S.F., see Bolt, P.H.	89 (1995) 339
Hong, SA., see Hong, J.K.	89 (1995) 229	Lobstein, N., E. Millon, A. Hachimi, J.F.	
Hou, H.W., see Ye, X.R.	89 (1995) 151	Muller, M. Alnot and J.J. Ehrhardt, De-	
Hultquist, G., see Gråsjö, L.	89 (1995) 21	position by laser ablation and characteri-	
		zation of titanium dioxide films on	00 (1005) 205
Ishida, H., see Yoshida, S.	89 (1995) 39	polyethylene-terephthalate	89 (1995) 307
Ito, S., see Kameoka, S.	89 (1995) 411	Lokere, K., see Donaton, R.A.	89 (1995) 221
Jo, B.H. and R.W. Vook, Dependence of		Maex, K., see Donaton, R.A.	89 (1995) 221
electromigration rate on applied electric		Magni, E. and G.A. Somorjai, Preparation	
potential	89 (1995) 237	of a model Ziegler-Natta catalyst. Sur-	
F		face science studies of magnesium chlo-	
Kameoka, S., T. Kuriyama, M. Kuroda, S.		ride thin film deposited on gold and its	/
Ito and K. Kunimori, The chemical in-		interaction with titanium chloride	89 (1995) 187
teraction between plasma-excited nitro-		Masuda, T., see Arai, M.	89 (1995) 11
	00 (100%) 411	Mathur, B.K., see Rao, M.V.H.	89 (1995) 417
gen and the surface of titanium dioxide	89 (1995) 411	Meda, L., see Cerofolini, G.F.	89 (1995) 351
Kamidoi, S., see Butman, M.F.	89 (1995) 323	Meda, L., see Cerofolini, G.F.	89 (1995) 361
Katoh, T., see Hanebuchi, M.	89 (1995) 113	Medvedev, A.S., see Shklyaev, A.A.	89 (1995) 49
Kawano, H., see Butman, M.F.	89 (1995) 323	Meister, G., see Kürpick, U.	89 (1995) 383
Kubo, M., R. Miura, R. Yamauchi, R.		Millon, E., see Lobstein, N.	89 (1995) 307
Vetrivel and A. Miyamoto, Mechanism		Milun, M., see Valla, T.	89 (1995) 375
of the formation of ultrafine gold parti-		Mitchell, K.A.R., see Wong, P.C.	89 (1995) 255
cles on MgO(100) as investigated by		Mitchell, K.A.R., see Li, Y.S.	89 (1995) 263
molecular dynamics and computer		Miura, R., see Kubo, M.	89 (1995) 131
graphics	89 (1995) 131	Miyamoto, A., see Kubo, M.	89 (1995) 131
Kunimori, K., see Kameoka, S.	89 (1995) 411	Morita, K., see Hanebuchi, M.	89 (1995) 113
Kuriyama, T., see Kameoka, S.	89 (1995) 411	Mudholkar, M.S., see Lee, H.J.	89 (1995) 121
Kuroda, M., see Kameoka, S.	89 (1995) 411	Muller, J.F., see Lobstein, N.	89 (1995) 307
Kürpick, U., G. Meister and A. Goldmann,		Müller, K., see Starke, U.	89 (1995) 175
Diffusion of Ag on Cu(110) and Cu(111)		Muñoz-Guillena, M.J., A. Linares-Solano	
studied by spatially resolved UV-photo-		and C. Salinas-Martínez de Lecea, A	
emission	89 (1995) 383	new parameter to characterize lime-	
Küttel, O.M., see Gröning, P.	89 (1995) 83	stones as SO ₂ sorbents	89 (1995) 197
Rutter, O.M., see Groning, 1.			
La Bruna, G., see Cerofolini, G.F.	89 (1995) 361	Nakamura, J., see Butman, M.F.	89 (1995) 323

Nishimura, Y., H. Ujita and M. Tsuji, Tan- talum oxide film formation by excimer laser ablation	89 (1995) 393	Tomizuka, H. and A. Ayame, A graphical analysis of transient response curves at an early stage in SIMS depth profiling	
	89 (1995) 11	using a ¹³³ Cs ⁺ beam	89 (1995) 281
Nishiyama, Y., see Arai, M.	09 (1993) 11		
Oh, IH., see Hong, J.K.	89 (1995) 229	Tsuji, M., see Nishimura, Y.	89 (1995) 393
Oil, 1H., see Holig, J.R.	07 (1993) 229	Ujita, H., see Nishimura, Y.	89 (1995) 393
Pervan, P., see Valla, T.	89 (1995) 375	Ojita, H., see Pisiiiilura, 1.	09 (1993) 393
Porto, A., see Scandurra, A.	89 (1995) 1	Vers T I Ishing and D HeatsWard	
Powell, C.J., Elemental binding energies for		Vaara, T., J. Lahtinen and P. Hautojärvi, Reactions of CO and NO on Mg pro-	
X-ray photoelectron spectroscopy	89 (1995) 141	moted cobalt	89 (1995) 103
Puglisi, O., see Scandurra, A.	89 (1995) 1	Valla, T., P. Pervan and M. Milun, Interac-	89 (1993) 103
Puppin, E., see Vavassori, P.	89 (1995) 93	tion of oxygen and silver on the V(100)	
***		surface	89 (1995) 375
Qiu, SL., see Ruckman, M.W.	89 (1995) 401	Vavassori, P., L. Callegaro and E. Puppin,	09 (1993) 373
		Ultraviolet inverse photoemission study	
Ramadan, A.A., see Ashour, A.	89 (1995) 159	of the oxidation of YFe ₂	89 (1995) 93
Rao, M.V.H., V. Srinivas, V.V. Rao, B.K.		Verbeeck, R., see Donaton, R.A.	89 (1995) 221
Mathur and K.L. Chopra, Observation		Vergnat, M., see Hadj Zoubir, N.	89 (1995) 35
of field-induced fragmentation of nickel		Vetrivel, R., see Kubo, M.	89 (1995) 131
clusters using Scanning Tunneling Mi-		Vook, R.W., see Jo, B.H.	89 (1995) 237
croscopy	89 (1995) 417	7 00k, 10. W., 500 50, D.11.	07 (1773) 231
Rao, V.V., see Rao, M.V.H.	89 (1995) 417	Wang, T., see Fang, Y.	89 (1995) 331
Ruckman, M.W., SL. Qiu and M. Stron-		Wang, X.K., N.F. Shen, Z.S. Yang and	69 (1993) 331
gin, A photoelectron study of the oxida-		H.C. Gu, Activation treatments and sur-	
tion of Ta(110) and thin aluminum lay-		face study of amorphous Fe ₉₀ Zr ₁₀ and	
ers on Ta(110)	89 (1995) 401		89 (1995) 297
		Fe _{87.8} Zr ₁₀ Co ₂ Al _{0.2} catalysts Wang, Y., see Chen, X.	89 (1995) 169
Salinas-Martínez de Lecea, C., see Muñoz-		Wong, P.C., Y.S. Li, M.Y. Zhou and K.A.R.	07 (1773) 107
Guillena, M.J.	89 (1995) 197	Mitchell, XPS investigations of the in-	
Sanyal, S., see Chattopadhyay, P.	89 (1995) 205	teractions of hydrogen with thin films of	
Scandurra, A., A. Porto and O. Puglisi,		zirconium oxide. I. Hydrogen treatments	
SIMS microprofiles of Pb-5%Sn solder		on a 10 Å thick film	89 (1995) 255
joints in electronic devices after acceler-		Wong, P.C., see Li, Y.S.	89 (1995) 263
ated life tests	89 (1995) 1	Wu, S. and D. Haneman, Cadmium se-	07 (1770) 200
Schlapbach, L., see Gröning, P.	89 (1995) 83	lenide-amorphous hydrogenated silicon	
Seo, M., see Gråsjö, L.	89 (1995) 21	heterostructures	89 (1995) 289
Shen, N.F., see Wang, X.K.	89 (1995) 297		. ()
Shklyaev, A.A. and A.S. Medvedev,		Xin, X.Q., see Ye, X.R.	89 (1995) 151
Plasma-enhanced reactively evaporated	00 (1008) 10	Xue, G., J. Ding and P. Cheng, Growth of a	07 (1775) 151
deposition of SiO ₂ films	89 (1995) 49	surface film on copper from benzotria-	
Somorjai, G.A., see Magni, E.	89 (1995) 187	zole solutions	89 (1995) 77
Srinivas, V., see Rao, M.V.H.	89 (1995) 417		. (
Starke, U., Ch. Bram, PR. Steiner, W.		Yamauchi, R., see Kubo, M.	89 (1995) 131
Hartner, L. Hammer, K. Heinz and K.		Yanagisawa, Y., Oxygen exchange between	07 (1773) 131
Müller, The (0001)-surface of 6H-SiC:	89 (1995) 175	adsorbed NO and MgO surfaces	89 (1995) 251
morphology, composition and structure	89 (1995) 175	Yang, Z.S., see Wang, X.K.	89 (1995) 297
Steiner, PR., see Starke, U.	89 (1995) 401	Ye, X.R., H.W. Hou, X.Q. Xin and C.F.	07 (1775) 271
Strongin, M., see Ruckman, M.W.	89 (1995) 401	Hammer, M-S (M = Mo, W) cluster	
Tan, K.L., see Gråsjö, L.	89 (1995) 21	compound films on copper surfaces	89 (1995) 151
Tang, YQ., see Fang, Y.	89 (1995) 331	Yoshida, S. and H. Ishida, An investigation	07 (1770) 101
Tejedor, P. and P.S. Domínguez, Surface	07 (1773) 331	of the thermal stability of undecylimida-	
kinetics and morphology of ArF laser-		zole on copper by FT-IR reflection-ab-	
assisted etching of (113)A GaAs in a		sorption spectroscopy	89 (1995) 39
Cl ₂ environment	89 (1995) 271	1	(
Thompson, L.T., see Lee, H.J.	89 (1995) 121	Zhou, M.Y., see Wong, P.C.	89 (1995) 255
,,,,	\\		07 (1770) 200

Subject index

Ablation Activation treatments and surface study of amorphous $Fe_{90}Zr_{10}$ and $Fe_{87.8}Zr_{10}Co_2$ Al $_{0.2}$ catalysts, X.K. Wang, N.F. Shen, Deposition by laser ablation and characteri-Z.S. Yang and H.C. Gu 89 (1995) 297 zation of titanium dioxide films on A photoelectron study of the oxidation of polyethylene-terephthalate, N. Lobstein, Ta(110) and thin aluminum layers on E. Millon, A. Hachimi, J.F. Muller, M. Ta(110), M.W. Ruckman, S.-L. Qiu and Alnot and J.J. Ehrhardt 89 (1995) 307 M. Strongin 89 (1995) 401 Tantalum oxide film formation by excimer laser ablation, Y. Nishimura, H. Ujita and M. Tsuji 89 (1995) 393 Aluminium oxide XPS studies of the effect of Mn on Pd/ Alkali metals Al₂O₃, P.C. L'Argentière, M.G. Cañón and N.S. Figoli 89 (1995) 63 A graphical analysis of transient response A study of the composition distribution at curves at an early stage in SIMS depth profiling using a ¹³³Cs⁺ beam, H. the Ti/Al2O3 interface using the MCs+-SIMS technique, X. Chen and Y. Tomizuka and A. Ayame 89 (1995) 281 89 (1995) 169 Wang Influence of surface charge on thermal posi-Interfacial reaction of NiO with Al2O3 tive ion emission from potassium bro-(11 $\overline{2}$ 0) and polycrystalline α -Al₂O₃, mide, M.F. Butman, J. Nakamura, S. P.H. Bolt, S.F. Lobner, J.W. Geus and Kamidoi and H. Kawano 89 (1995) 323 FHPM Habraken 89 (1995) 339 Ammonia Alloys Temperature-programmed desorption and SIMS microprofiles of Pb-5%Sn solder decomposition of NH₃ over molybdejoints in electronic devices after accelernum nitride films, H.J. Lee, J.-G. Choi, ated life tests, A. Scandurra, A. Porto C.W. Colling, M.S. Mudholkar and L.T. and O. Puglisi 89 (1995) 1 89 (1995) 121 Thompson Ultraviolet inverse photoemission study of Activation treatments and surface study of the oxidation of YFe2, P. Vavassori, L. amorphous $Fe_{90}Zr_{10}$ and $Fe_{87.8}Zr_{10}Co_2$ Al $_{0.2}$ catalysts, X.K. Wang, N.F. Shen, Callegaro and E. Puppin 89 (1995) 93 Activation treatments and surface study of Z.S. Yang and H.C. Gu 89 (1995) 297 amorphous Fe₉₀ Zr₁₀ and Fe_{87.8}Zr₁₀Co₂ Al_{0.2} catalysts, X.K. Wang, N.F. Shen, Atomic force microscopy Z.S. Yang and H.C. Gu 89 (1995) 297 Thickness determination of uniform over-Aluminium layers on rough substrates by angle-dependent XPS, P.L.J. Gunter and J.W. 89 (1995) 69 X-ray photoelectron spectroscopic study of Niemantsverdriet room-temperature evolution of oxide-Atomic force microscopy determination of covered hydrogenated amorphous silithe topography of fly-ash particles, C.M. 89 (1995) 57 89 (1995) 97 con/aluminium interface, C. Anandan Demanet

Deposition by laser ablation and characterization of titanium dioxide films on		Catalysis	
polyethylene-terephthalate, N. Lobstein,			
E. Millon, A. Hachimi, J.F. Muller, M.		The distribution of activation energy for	
Alnot and J.J. Ehrhardt	89 (1995) 307	hydrogen desorption over silica-sup-	
Alnot and J.J. Emmardt	09 (1993) 307	ported nickel catalysts determined from	
		temperature-programmed desorption	
Auger electron spectroscopy		spectra, M. Arai, Y. Nishiyama, T. Ma-	
1		suda and K. Hashimoto	89 (1995) 11
Characteristics of this As films described		Preparation of a model Ziegler-Natta cata-	
Characterization of thin Ag films deposited		lyst. Surface science studies of magne-	
onto $InP(001)$ -p(2 × 4) surface at room		sium chloride thin film deposited on	
temperature by means of LEED,		gold and its interaction with titanium	
RHEED, AES and RBS-channeling		chloride, E. Magni and G.A. Somorjai	89 (1995) 187
techniques, M. Hanebuchi, T. Katoh and		Activation treatments and surface study of	07 (1775) 107
K. Morita	89 (1995) 113		
M-S ($M = Mo, W$) cluster compound films		amorphous Fe ₉₀ Zr ₁₀ and Fe _{87.8} Zr ₁₀ Co ₂	
on copper surfaces, X.R. Ye, H.W. Hou,		Al _{0.2} catalysts, X.K. Wang, N.F. Shen,	00 (1005) 207
X.Q. Xin and C.F. Hammer	89 (1995) 151	Z.S. Yang and H.C. Gu	89 (1995) 297
Quantitative correction of backscattering in			
Auger electron spectroscopy of thin		Cobalt	
films, G. Lévêque and J. Bonnet	89 (1995) 211		
Activation treatments and surface study of	07 (1770) 211	Reactions of CO and NO on Mg promoted	
		cobalt, T. Vaara, J. Lahtinen and P.	
amorphous Fe ₉₀ Zr ₁₀ and Fe _{87.8} Zr ₁₀ Co ₂			00 (1005) 103
Al _{0.2} catalysts, X.K. Wang, N.F. Shen,	00 (1005) 207	Hautojärvi	89 (1995) 103
Z.S. Yang and H.C. Gu	89 (1995) 297	Etching of CoSi ₂ in HF-based solutions,	
Interaction of oxygen and silver on the		R.A. Donaton, K. Lokere, R. Verbeeck	
V(100) surface, T. Valla, P. Pervan and		and K. Maex	89 (1995) 221
M. Milun	89 (1995) 375	Activation treatments and surface study of	
		amorphous Fe ₉₀ Zr ₁₀ and Fe _{87.8} Zr ₁₀ Co ₂	
Cadmium selenide		Al _{0.2} catalysts, X.K. Wang, N.F. Shen,	
Cuumum Scientic		Z.S. Yang and H.C. Gu	89 (1995) 297
Codmium calonida amarahana hudragan			
Cadmium selenide-amorphous hydrogen-		Computer simulations	
ated silicon heterostructures, S. Wu and	00 (4005) 200		
D. Haneman	89 (1995) 289	Mechanism of the formation of ultrafine	
Cadmium telluride		gold particles on MgO(100) as investi-	
		gated by molecular dynamics and com-	
		puter graphics, M. Kubo, R. Miura, R.	
Thermal effects on structural characteriza-		Yamauchi, R. Vetrivel and A. Miyamoto	89 (1995) 131
tion of evaporated CdTe films during			
and after deposition, A. Ashour, M.R.		Copper	
Ebeid, N. El-Kadry, M.F. Ahmed and		Соррег	
A.A. Ramadan	89 (1995) 159		
		An investigation of the thermal stability of	
0.1.		undecylimidazole on copper by FT-IR	
Calcium		reflection-absorption spectroscopy, S.	
		Yoshida and H. Ishida	89 (1995) 39
A new parameter to characterize limestones		Growth of a surface film on copper from	
as SO ₂ sorbents, M.J. Muñoz-Guillena,		benzotriazole solutions, G. Xue, J. Ding	
A. Linares-Solano and C. Salinas-		and P. Cheng	89 (1995) 77
Martínez de Lecea	89 (1995) 197	M-S (M = Mo, W) cluster compound films	
Martinez de Lecea	07 (1773) 177	on copper surfaces, X.R. Ye, H.W. Hou,	
		X.Q. Xin and C.F. Hammer	89 (1995) 151
Carbon monoxide		Dependence of electromigration rate on ap-	07 (1773) 131
Denotions of CO and NO M		plied electric potential, B.H. Jo and R.W.	90 (1005) 225
Reactions of CO and NO on Mg promoted		Vook	89 (1995) 237
cobalt, T. Vaara, J. Lahtinen and P.	00 (1057) :	Diffusion of Ag on Cu(110) and Cu(111)	
Hautojärvi	89 (1995) 103	studied by spatially resolved UV-photo-	

emission, U. Kürpick, G. Meister and A. Goldmann	89 (1995) 383	Activation treatments and surface study of amorphous Fe ₉₀ Zr ₁₀ and Fe _{87.8} Zr ₁₀ Co ₂	
		Al _{0.2} catalysts, X.K. Wang, N.F. Shen,	
Electrical properties		Z.S. Yang and H.C. Gu Deposition by laser ablation and characteri-	89 (1995) 297
Capacitance-voltage characteristics of		zation of titanium dioxide films on polyethylene-terephthalate, N. Lobstein,	
Schottky barrier diode in the presence of		E. Millon, A. Hachimi, J.F. Muller, M.	
deep-level impurities and series resis- tance, P. Chattopadhyay and S. Sanyal	89 (1995) 205	Alnot and J.J. Ehrhardt Interfacial reaction of NiO with Al ₂ O ₃	89 (1995) 307
Dependence of electromigration rate on ap-		(11 $\bar{2}$ 0) and polycrystalline α -Al ₂ O ₃ ,	
plied electric potential, B.H. Jo and R.W. Vook	89 (1995) 237	P.H. Bolt, S.F. Lobner, J.W. Geus and	00 (4005) 000
Cadmium selenideamorphous hydrogen-	07 (1773) 231	F.H.P.M. Habraken	89 (1995) 339
ated silicon heterostructures, S. Wu and	22 (222) 222	Ellipsometry	
D. Haneman Influence of surface charge on thermal posi-	89 (1995) 289	Litipsometry	
tive ion emission from potassium bro-		Plasma-enhanced reactively evaporated de-	
mide, M.F. Butman, J. Nakamura, S.	00 (1005) 222	position of SiO ₂ films, A.A. Shklyaev	00 (1005) 40
Kamidoi and H. Kawano	89 (1995) 323	and A.S. Medvedev Deposition by laser ablation and characteri-	89 (1995) 49
Electromigration		zation of titanium dioxide films on	
Lieth omigration		polyethylene-terephthalate, N. Lobstein, E. Millon, A. Hachimi, J.F. Muller, M.	
Dependence of electromigration rate on ap-		Alnot and J.J. Ehrhardt	89 (1995) 307
plied electric potential, B.H. Jo and R.W.	00 (1005) 225	Tantalum oxide film formation by excimer	
Vook	89 (1995) 237	laser ablation, Y. Nishimura, H. Ujita and M. Tsuji	89 (1995) 393
Electron diffraction			
		Epitaxy	
Characterization of thin Ag films deposited onto InP(001)-p(2 × 4) surface at room		Diffusion of Ag on Cu(110) and Cu(111)	
temperature by means of LEED,		studied by spatially resolved UV-photo-	
RHEED, AES and RBS-channeling		emission, U. Kürpick, G. Meister and A.	()
techniques, M. Hanebuchi, T. Katoh and K. Morita	89 (1995) 113	Goldmann	89 (1995) 383
	(/	Etching	
Electron energy loss spectroscopy		Liching	
		Etching of CoSi2 in HF-based solutions,	
The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke,		R.A. Donaton, K. Lokere, R. Verbeeck	89 (1995) 221
Ch. Bram, PR. Steiner, W. Hartner, L.		and K. Maex Surface kinetics and morphology of ArF	69 (1993) 221
Hammer, K. Heinz and K. Müller	89 (1995) 175	laser-assisted etching of (113)A GaAs in	
		a Cl ₂ environment, P. Tejedor and P.S. Domínguez	89 (1995) 271
Electron microscopy		Dominguez	09 (1993) 271
Etching of CoSi ₂ in HF-based solutions,		Evaporation	
R.A. Donaton, K. Lokere, R. Verbeeck	00 (1005) 221	T 1 6	
and K. Maex The effect of anodic polarization on a Ag	89 (1995) 221	Thermal effects on structural characteriza- tion of evaporated CdTe films during	
electrode deposited on YSZ solid elec-		and after deposition, A. Ashour, M.R.	
trolyte, J.K. Hong, IH. Oh, SA. Hong	89 (1995) 229	Ebeid, N. El-Kadry, M.F. Ahmed and A.A. Ramadan	89 (1995) 159
and W.Y. Lee Dependence of electromigration rate on ap-	07 (1793) 449	Dependence of electromigration rate on ap-	07 (1773) 139
plied electric potential, B.H. Jo and R.W.			
Vook	89 (1995) 237	plied electric potential, B.H. Jo and R.W. Vook	89 (1995) 237

Cadmium selenide-amorphous hydrogen- ated silicon heterostructures, S. Wu and		Hydrogen	
D. Haneman	89 (1995) 289	The distribution of estimation account for	
Interfacial reaction of NiO with Al ₂ O ₃	0. (2) ==.	The distribution of activation energy for	
(11 $\overline{2}$ 0) and polycrystalline α -Al ₂ O ₃ ,		hydrogen desorption over silica-sup-	
P.H. Bolt, S.F. Lobner, J.W. Geus and		ported nickel catalysts determined from	
F.H.P.M. Habraken	89 (1995) 339	temperature-programmed desorption	
r.n.r.m. nabraken	09 (1993) 339	spectra, M. Arai, Y. Nishiyama, T. Ma-	
		suda and K. Hashimoto	89 (1995) 11
Gallium arsenide		XPS investigations of the interactions of	
		hydrogen with thin films of zirconium	
Surface kinetics and morphology of ArF		oxide. I. Hydrogen treatments on a 10 Å	
laser-assisted etching of (113)A GaAs in		thick film, P.C. Wong, Y.S. Li, M.Y.	
		Zhou and K.A.R. Mitchell	89 (1995) 255
a Cl ₂ environment, P. Tejedor and P.S.	00 (1006) 271	XPS investigations of the interactions of	07 (1775) 255
Domínguez	89 (1995) 271		
		hydrogen with thin films of zirconium	
Gold		oxide. II. Effects of heating a 26 Å thick	
		film after treatment with a hydrogen	
Mechanism of the formation of ultrafine		plasma, Y.S. Li, P.C. Wong and K.A.R.	
		Mitchell	89 (1995) 263
gold particles on MgO(100) as investi-		Cadmium selenide-amorphous hydrogen-	
gated by molecular dynamics and com-		ated silicon heterostructures, S. Wu and	
puter graphics, M. Kubo, R. Miura, R.		D. Haneman	89 (1995) 289
Yamauchi, R. Vetrivel and A. Miyamoto	89 (1995) 131	D. Halleman	07 (1775) 207
Preparation of a model Ziegler-Natta cata-			
lyst. Surface science studies of magne-		Indium phosphide	
sium chloride thin film deposited on			
gold and its interaction with titanium		Characterization of thin Ag films deposited	
chloride, E. Magni and G.A. Somorjai	89 (1995) 187	onto $InP(001)$ -p(2 × 4) surface at room	
chiorido, 2. Magni and O.M. Doniorjai	07 (1775) 101	temperature by means of LEED,	
Halogenides		RHEED, AES and RBS-channeling	
		techniques, M. Hanebuchi, T. Katoh and	
Preparation of a model Ziegler-Natta cata-		K. Morita	89 (1995) 113
lyst. Surface science studies of magne-			
sium chloride thin film deposited on		Infrared spectroscopy	
gold and its interaction with titanium		niji ui cu specii oscopy	
chloride, E. Magni and G.A. Somorjai	89 (1995) 187		
	09 (1993) 107	An investigation of the thermal stability of	
Influence of surface charge on thermal posi-		undecylimidazole on copper by FT-IR	
tive ion emission from potassium bro-		reflection-absorption spectroscopy, S.	
mide, M.F. Butman, J. Nakamura, S.		Yoshida and H. Ishida	89 (1995) 39
Kamidoi and H. Kawano	89 (1995) 323	Plasma-enhanced reactively evaporated de-	
		position of SiO ₂ films, A.A. Shklyaev	
Hydrides		and A.S. Medvedev	89 (1995) 49
11)41 1405		Growth of a surface film on copper from	0) (1))0)
		benzotriazole solutions, G. Xue, J. Ding	
Surface reactions on palladium hydride in		_	00 (1005) ==
vacuum, air and water studied in situ		and P. Cheng	89 (1995) 77
with mass spectrometry, L. Gråsjö, G.		M-S ($M = Mo, W$) cluster compound films	
Hultquist, K.L. Tan and M. Seo	89 (1995) 21	on copper surfaces, X.R. Ye, H.W. Hou,	
		X.Q. Xin and C.F. Hammer	89 (1995) 151
Hydrocarbons		The chemical interaction between plasma-	
Tryarocarbons		excited nitrogen and the surface of tita-	
		nium dioxide, S. Kameoka, T. Kuriyama,	
An investigation of the thermal stability of		M. Kuroda, S. Ito and K. Kunimori	89 (1995) 411
undecylimidazole on copper by FT-IR		M. Raioda, O. No and R. Raimion	07 (1775) 411
reflection-absorption spectroscopy, S.			
Yoshida and H. Ishida	89 (1995) 39	Interfaces	
Growth of a surface film on copper from			
benzotriazole solutions, G. Xue, J. Ding		X-ray photoelectron spectroscopic study of	
and P. Cheng	89 (1995) 77	room-temperature evolution of oxide-	
and I. Onling	07 (1773) //	room temperature evolution of oxide-	

covered hydrogenated amorphous silicon/aluminium interface, C. Anandan A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs ⁺ -SIMS technique, X. Chen and Y. Wang	89 (1995) 57 89 (1995) 169	temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, Ch. Bram, PR. Steiner, W. Hartner, L.	89 (1995) 113
on scattering		Hammer, K. Heinz and K. Muller	89 (1995) 175
Characterization of thin Ag films deposited onto InP(001)-p(2 × 4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and		Magnesium Reactions of CO and NO on Mg promoted cobalt, T. Vaara, J. Lahtinen and P. Hautojärvi	89 (1995) 103
etching of CoSi ₂ in HF-based solutions, R.A. Donaton, K. Lokere, R. Verbeeck		lyst. Surface science studies of magne- sium chloride thin film deposited on	
nterfacial reaction of NiO with Al_2O_3 (11 $\bar{2}0$) and polycrystalline α -Al $_2O_3$,	89 (1995) 221	gold and its interaction with titanium chloride, E. Magni and G.A. Somorjai	89 (1995) 187
F.H.P.M. Habraken	89 (1995) 339	Magnesium oxide	
ron		Mechanism of the formation of ultrafine gold particles on MgO(100) as investi- gated by molecular dynamics and com-	
Iltraviolet inverse photoemission study of the oxidation of YFe ₂ , P. Vavassori, L. Callegaro and E. Puppin activation treatments and surface study of amorphous Fe ₉₀ Zr ₁₀ and Fe _{87.8} Zr ₁₀ Co ₂	89 (1995) 93	puter graphics, M. Kubo, R. Miura, R. Yamauchi, R. Vetrivel and A. Miyamoto Oxygen exchange between adsorbed NO and MgO surfaces, Y. Yanagisawa	89 (1995) 131 89 (1995) 251
Al _{0.2} catalysts, X.K. Wang, N.F. Shen, Z.S. Yang and H.C. Gu	89 (1995) 297	Manganese	
aser processing		XPS studies of the effect of Mn on Pd/ Al ₂ O ₃ , P.C. L'Argentière, M.G. Cañón and N.S. Fígoli	89 (1995) 63
laser-assisted etching of (113)A GaAs in a Cl ₂ environment, P. Tejedor and P.S.	00 (4005) 074	Mass spectroscopy	
Dominguez antalum oxide film formation by excimer laser ablation, Y. Nishimura, H. Ujita and M. Tsuji	89 (1995) 271 89 (1995) 393	Surface reactions on palladium hydride in vacuum, air and water studied in situ with mass spectrometry, L. Gråsjö, G. Hultquist, K.L. Tan and M. Seo	89 (1995) 21
ead		Molybdenum	
IMS microprofiles of Pb-5%Sn solder joints in electronic devices after acceler- ated life tests, A. Scandurra, A. Porto and O. Puglisi	89 (1995) 1	Temperature-programmed desorption and decomposition of NH ₃ over molybdenum nitride films, H.J. Lee, JG. Choi, C.W. Colling, M.S. Mudholkar and L.T.	80 (1005) 121
ow energy electron diffraction		M-S (M = Mo, W) cluster compound films on copper surfaces, X.R. Ye, H.W. Hou,	89 (1995) 121
haracterization of thin Ag films deposited onto $InP(001)$ - $p(2 \times 4)$ surface at room		X.Q. Xin and C.F. Hammer	89 (1995) 151
	con/aluminium interface, C. Anandan a study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs ⁺ -SIMS technique, X. Chen and Y. Wang on scattering con scattering	con/aluminium interface, C. Anandan at the Ti/Al ₂ O ₃ interface using the MCs*-SIMS technique, X. Chen and Y. Wang On scattering con scat	son/aluminium interface, C. Anandan to the Ti/Al ₂ O ₃ interface using the MCs*-SIMS technique, X. Chen and Y. Wang Wang Bo (1995) 169 Baracterization of thin Ag films deposited onto InP(001)-p(2 × 4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita Ch. Bram, PR. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Müller Magnesium Magnesium Reactions of CO and NO on Mg promoted cobalt, T. Varan, J. Lahtinen and P. Hautojārvi Preparation of a model Ziegler-Nata cardlyst. Surface science studies of magnesium chloride, E. Magni and G.A. Somorjai Magnesium 89 (1995) 113 89 (1995) 121 Reactions of CO and NO on Mg promoted cobalt, T. Varan, J. Lahtinen and P. Hautojārvi Preparation of a model Ziegler-Nata cardlyst. Surface science studies of magnesium chloride, E. Magni and G.A. Somorjai Magnesium oxide 89 (1995) 221 Magnesium oxide Magnesium oxide Mechanism of the formation of ultrafine gold particles on MgO(100) as investigated by molecular dynamics and computer graphics, M. Kabo, R. Miura, Yamauchi, R. Vetrivet and A. Miyamoto Oxygen exchange between adsorbed NO and MgO surfaces, Y. Yanagisawa Magnesium oxide Mechanism of the formation of ultrafine gold particles on MgO(100) as investigated by molecular dynamics and computer graphics, M. Kabo, R. Miura, Yamauchi, R. Vetrivet and A. Miyamoto Oxygen exchange between adsorbed NO and MgO surfaces, Y. Yanagisawa Magnesium oxide Magnesium oxid

Nickel		XPS investigations of the interactions of hydrogen with thin films of zirconium	
Interfacial reaction of NiO with Al_2O_3 (11 $\overline{2}O$) and polycrystalline α - Al_2O_3 , P.H. Bolt, S.F. Lobner, J.W. Geus and		oxide. I. Hydrogen treatments on a 10 Å thick film, P.C. Wong, Y.S. Li, M.Y. Zhou and K.A.R. Mitchell	89 (1995) 255
F.H.P.M. Habraken Observation of field-induced fragmentation	89 (1995) 339	XPS investigations of the interactions of hydrogen with thin films of zirconium	
of nickel clusters using Scanning Tun- neling Microscopy, M.V.H. Rao, V. Srinivas, V.V. Rao, B.K. Mathur and		oxide. II. Effects of heating a 26 Å thick film after treatment with a hydrogen plasma, Y.S. Li, P.C. Wong and K.A.R.	(
K.L. Chopra	89 (1995) 417	Mitchell Interfacial reaction of NiO with Al_2O_3 (11 $\overline{2}O_3$) and polycrystalline α - Al_2O_3 ,	89 (1995) 263
Nitric oxide		P.H. Bolt, S.F. Lobner, J.W. Geus and F.H.P.M. Habraken	89 (1995) 339
Reactions of CO and NO on Mg promoted cobalt, T. Vaara, J. Lahtinen and P.	00 (4005) 400	Tantalum oxide film formation by excimer laser ablation, Y. Nishimura, H. Ujita	89 (1995) 393
Hautojärvi Oxygen exchange between adsorbed NO and	89 (1995) 103	and M. Tsuji	89 (1993) 393
MgO surfaces, Y. Yanagisawa	89 (1995) 251	Oxygen	
Nitrides		Interaction of oxygen and silver on the V(100) surface, T. Valla, P. Pervan and	
Temperature-programmed desorption and decomposition of NH ₃ over molybde-		M. Milun	89 (1995) 375
num nitride films, H.J. Lee, JG. Choi,		Palladium	
C.W. Colling, M.S. Mudholkar and L.T. Thompson	89 (1995) 121		
	27 (1772) 122	Surface reactions on palladium hydride in vacuum, air and water studied in situ	
Nitrogen		with mass spectrometry, L. Gråsjö, G. Hultquist, K.L. Tan and M. Seo	89 (1995) 21
The chemical interaction between plasma- excited nitrogen and the surface of tita-		XPS studies of the effect of Mn on Pd/ Al ₂ O ₃ , P.C. L'Argentière, M.G. Cañón and N.S. Fígoli	89 (1995) 63
nium dioxide, S. Kameoka, T. Kuriyama, M. Kuroda, S. Ito and K. Kunimori	89 (1995) 411	and N.S. Figori	07(1775) 05
,		Photoelectron spectroscopy	
Oxidation			
		Plasma-enhanced reactively evaporated de-	
Ultraviolet inverse photoemission study of the oxidation of YFe ₂ , P. Vavassori, L.		position of SiO ₂ films, A.A. Shklyaev and A.S. Medvedev	89 (1995) 49
Callegaro and E. Puppin	89 (1995) 93	X-ray photoelectron spectroscopic study of	
Enhanced silicon oxidation in O2 and O2:F2,		room-temperature evolution of oxide-	
G.F. Cerofolini, G. La Bruna and L. Meda	20 (1005) 2(1	covered hydrogenated amorphous sili- con/aluminium interface, C. Anandan	89 (1995) 57
A photoelectron study of the oxidation of	89 (1995) 361	XPS studies of the effect of Mn on Pd/	07 (1770) 51
Ta(110) and thin aluminum layers on		Al ₂ O ₃ , P.C. L'Argentière, M.G. Cañón	
Ta(110), M.W. Ruckman, SL. Qiu and	(and N.S. Figoli Thickness determination of uniform over-	89 (1995) 63
M. Strongin	89 (1995) 401	layers on rough substrates by angle-de- pendent XPS, P.L.J. Gunter and J.W.	
Oxides		Niemantsverdriet	89 (1995) 69
A new parameter to characterize limestones		Interaction of low-energy ions (< 10 eV) with polymethylmethacrylate during	
as SO ₂ sorbents, M.J. Muñoz-Guillena,		plasma treatment, P. Gröning, O.M.	
A. Linares-Solano and C. Salinas-		Küttel, M. Collaud-Coen, G. Dietler and	
Martínez de Lecea	89 (1995) 197	L. Schlapbach	89 (1995) 83

Reactions of CO and NO on Mg promoted		Plasma processing	
cobalt, T. Vaara, J. Lahtinen and P.	00 (1005) 102		
Hautojärvi Elemental binding energies for X-ray photo-	89 (1995) 103		
electron spectroscopy, C.J. Powell M-S (M = Mo, W) cluster compound films	89 (1995) 141	Plasma-enhanced reactively evaporated de- position of SiO ₂ films, A.A. Shklyaev and A.S. Medvedev	89 (1995) 49
on copper surfaces, X.R. Ye, H.W. Hou,	()	Interaction of low-energy ions (< 10 eV)	. (2)
X.Q. Xin and C.F. Hammer The effect of anodic polarization on a Ag electrode deposited on YSZ solid electrolyte, J.K. Hong, IH. Oh, SA. Hong	89 (1995) 151	with polymethylmethacrylate during plasma treatment, P. Gröning, O.M. Küttel, M. Collaud-Coen, G. Dietler and	
and W.Y. Lee	89 (1995) 229	L. Schlapbach	89 (1995) 83
XPS investigations of the interactions of hydrogen with thin films of zirconium oxide. I. Hydrogen treatments on a 10 Å thick film, P.C. Wong, Y.S. Li, M.Y.		XPS investigations of the interactions of hydrogen with thin films of zirconium oxide. I. Hydrogen treatments on a 10 Å thick film, P.C. Wong, Y.S. Li, M.Y.	00 (4005) 257
Zhou and K.A.R. Mitchell	89 (1995) 255	Zhou and K.A.R. Mitchell	89 (1995) 255
XPS investigations of the interactions of hydrogen with thin films of zirconium oxide. II. Effects of heating a 26 Å thick film after treatment with a hydrogen plasma, Y.S. Li, P.C. Wong and K.A.R.		XPS investigations of the interactions of hydrogen with thin films of zirconium oxide. II. Effects of heating a 26 Å thick film after treatment with a hydrogen plasma, Y.S. Li, P.C. Wong and K.A.R.	00 (1005) 072
Mitchell	89 (1995) 263	Mitchell	89 (1995) 263
A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a ¹³³ Cs ⁺ beam, H.		Cadmium selenide-amorphous hydrogen- ated silicon heterostructures, S. Wu and D. Haneman	89 (1995) 289
Tomizuka and A. Ayame	89 (1995) 281	The chemical interaction between plasma- excited nitrogen and the surface of tita-	
Activation treatments and surface study of amorphous Fe ₉₀ Zr ₁₀ and Fe _{87.8} Zr ₁₀ Co ₂ Al _{0.2} catalysts, X.K. Wang, N.F. Shen,		nium dioxide, S. Kameoka, T. Kuriyama, M. Kuroda, S. Ito and K. Kunimori	89 (1995) 411
Z.S. Yang and H.C. Gu	89 (1995) 297		
Deposition by laser ablation and characteri- zation of titanium dioxide films on polyethylene-terephthalate, N. Lobstein,		Polymers	
E. Millon, A. Hachimi, J.F. Muller, M. Alnot and J.J. Ehrhardt	89 (1995) 307	An investigation of the thermal stability of	
Interaction of oxygen and silver on the	69 (1993) 307	undecylimidazole on copper by FT-IR	
V(100) surface, T. Valla, P. Pervan and		reflection-absorption spectroscopy, S.	
M. Milun	89 (1995) 375	Yoshida and H. Ishida	89 (1995) 39
Diffusion of Ag on Cu(110) and Cu(111) studied by spatially resolved UV-photo-		Growth of a surface film on copper from benzotriazole solutions, G. Xue, J. Ding	
emission, U. Kürpick, G. Meister and A.	00 (1000) 000	and P. Cheng	89 (1995) 77
Goldmann Tantalum oxide film formation by excimer laser ablation, Y. Nishimura, H. Ujita	89 (1995) 383	Interaction of low-energy ions (< 10 eV) with polymethylmethacrylate during plasma treatment, P. Gröning, O.M.	
and M. Tsuji	89 (1995) 393	Küttel, M. Collaud-Coen, G. Dietler and	00 (1005) 00
A photoelectron study of the oxidation of		L. Schlapbach Deposition by laser ablation and characteri-	89 (1995) 83
Ta(110) and thin aluminum layers on Ta(110), M.W. Ruckman, SL. Qiu and		zation of titanium dioxide films on	
M. Strongin	89 (1995) 401	polyethylene-terephthalate, N. Lobstein, E. Millon, A. Hachimi, J.F. Muller, M. Alnot and J.J. Ehrhardt	89 (1995) 307
Photoemission		Characterization of triplex RNA poly[rU] - poly[rA] · poly[rU] adsorbed on silver colloids by Fourier transform surface	
Ultraviolet inverse photoemission study of		enhanced Raman scattering and scan-	
the oxidation of YFe ₂ , P. Vavassori, L. Callegaro and E. Puppin	89 (1995) 93	ning tunneling microscopy, Y. Fang, C. Bai, T. Wang and YQ. Tang	89 (1995) 331

Characterization of triplex RNA polyfrUl-polyfrAl-polyfrAl adsorbed on silver colloids by Fourier transform surface enhanced Raman scattering and scanning tunnelling microscopy Scanning tunneling microscopy The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, Ch. Bram, FR. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Müller Characterization of triplex RNA polyfrUl-polyfral-polyfral-polyfral-good free discovered hydrogenated amalysis of transient response curves at an early stage in SIMS depth profiling using a 150 cs beam, H. Tomizuka and A. Ayame 89 (1995) 331 Scanning tunneling microscopy The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, Ch. Bram, FR. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Müller Characterization of triplex RNA polyfrul-polyfral-polyfral-polyfral-adostrode on silver colloids by Fourier transform surface enhanced Raman scattering and scanning tunneling microscopy, Y. Fang, C. Bai, T. Wang and YQ. Tang Observation of field-induced fragmentation of nickel clusters using Scanning Tunneling Microscopy, M.V.H. Rao, V. Srinivas, V.V. Rao, B.K. Mathur and K.L. Chopra Schottky barrier Capacitance-voltage characteristics of Schottky barrier diode in the presence of deep-level impurities and series resistance, P. Chattopadhyay and S. Sanyal Secondary ion mass spectrometry SiMS microprofiles of Pb-5%Sn solder joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the McS*-SMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a 150 cs beam, H. Tomizuka and A. Ayame X-ray photoelectron spectroscopy and physical converted surves at an early stage in SIMS depth profiling using a 150 cs beam, H. Tomizuka and A. Ayame X-ray photoelectron spectroscopy and physical coursel and early stage in SIMS depth profiling using a 150 cs be	
benzotriazole solutions, G. Xue, J. Ding and P. Cheng Characterization of triplex RNA poly[rU]-poly[rA]-poly[rU] adsorbed on silver colloids by Fourier transform surface enhanced Raman scattering and scanning tunneling microscopy The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, C. Bram, PR. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Müller Characterization of triplex RNA poly[rU]-poly[rA]-poly[rA] poly[rU] adsorbed on silver colloids by Fourier transform surface enhanced Raman scattering and scanning tunneling microscopy, Y. Fang, C. Bai, T. Wang and YQ. Tang Observation of field-induced fragmentation of nickel clusters using Scanning Tunneling Microscopy, M.V.H. Rao, V. Srinivas, V.V. Rao, B.K. Mathur and K.L. Chopra Schottky barrier Capacitance-voltage characteristics of Schottky barrier diode in the presence of deep-level impurities and series resistance, P. Chattopadhyay and S. Sanyal Secondary ion mass spectrometry SIMS microprofiles of Pb-5%Sn solder joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs*-SiMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a "15" Cs* beam, H. Tomizuka and A. Ayame Solution crystalline surface, Chemistry at silicon crystalline surfaces, GF. Cerofolini, and L. Meda Enhanced silicon betrostructures, S. Wu and D. Haneman Chemistry at silicon crystalline surface, GF. Cerofolini, and L. Meda Silicon carbide The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, Ch. Bram, PR. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Müller Silicon oxide Plasma-enhanced reactively evaporated deposition of SiO ₂ films, A.A. Shklyaev and A.S. Medvedev and A.S. Medvedev are all profiling using a "15" Cs* beam, H. Tomizuka and A. Ayame Silicon carbide Plasma-enhanced reactively evaporated deposition of	
polyfrAl polyfrUl adsorbed on silver colloids by Fourier transform surface enhanced Raman scattering and scanning tunneling microscopy. Y. Fang, C. Bai, T. Wang and YQ. Tang Scanning tunneling microscopy The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, Ch. Bram, PR. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Müller Characterization of triplex RNA polyfrUl-polyfrAl-polyfrUl adsorbed on silver colloids by Fourier transform surface enhanced Raman scattering and scanning tunneling microscopy, Y. Fang, C. Bai, T. Wang and YQ. Tang Observation of field-induced fragmentation of nickel clusters using Scanning Tunneling Microscopy, W.V.H. Rao, V. Srinivas, V.V. Rao, B.K. Mathur and K.L. Chopra Schottky barrier Capacitance-voltage characteristics of Schottky barrier diode in the presence of deep-level impurities and series resistance, P. Chattopadhyay and S. Sanyal Secondary ion mass spectrometry SIMS microprofiles of Pb-5%Sn solder joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al-2o, interface using the McS*-SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth Tomizuka and A. Ayame room-temperature evolution of oxide-covered hydrogenated amplysis of transient response curves at an early stage in SIMS depth profiling using a "B*Cs" beam, H. Tomizuka and A. Ayame The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, Ch. Bram, P-R. Steiner, W. Hartner, L. Meda The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, Ch. Bram, P-R. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Müller Schottky barrier Capacitance-voltage characteristics of Schottky barrier diode in the presence of deep-level impurities and series resistance, P. Chattopadhyay and S. Sanyal Solution carbide Characterization of thin Ag films deposited onto InP(001)-p(2 × 4) surface at room t	0 (1995) 35
Bai, T. Wang and YQ. Tang Scanning tunneling microscopy The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, Ch. Bram, PR. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Müller Characterization of triplex RNA poly[rU]-poly[rA]-poly[rU] adsorbed on silver colloids by Fourier transform surface enhanced Raman scattering and scanning tunneling microscopy, Y. Fang, C. Bai, T. Wang and YQ. Tang Observation of field-induced fragmentation of nickel clusters using Scanning Tunneling Microscopy, M.V.H. Rao, V. Srinivas, V.V. Rao, B.K. Mathur and K.L. Chopra Schottky barrier Capacitance-voltage characteristics of Schottky barrier diode in the presence of deep-level impurities and series resistance, P. Chattopadhyay and S. Sanyal Secondary ion mass spectrometry SIMS microprofiles of Pb-5%Sn solder joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs*-SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a 15 Cs* beam, H. Tomizuka and an arry stage in SIMS depth profiling using a 15 Cs* beam, H. Tomizuka and A. Ayame Servation of field-induced fragmentation of nickel clusters using Scanning Tunneling Microscopy, M.V.H. Rao, V. Srinivas, V.V. Rao, B.K. Mathur and K.L. Chopra Schottky barrier Silicon oxide Plasma-enhanced reactively evaporated deposition of SiO ₂ films, A.A. Shklyaev and A.S. Medvedev A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a 15 Cs* beam, H. Tomizuka and A. Ayame Silver Chemistry at silicon crystalline surfaces, G.F. Cerofolini and L. Meda Servation oxidation in O ₂ and O ₂ :F ₂ , G.F. Cerofolini, G. La Bruna and L. Meda Silicon carbide The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, Ch. Bram, PR. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Müller Silicon	0 (1995) 57
The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, Ch. Bram, PR. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Müller Characterization of triplex RNA poly[rU]- poly[rA]- poly[rU] adsorbed on silver colloids by Fourier transform surface enhanced Raman scattering and scanning tunneling microscopy, Y. Fang, C. Bai, T. Wang and YQ. Tang Observation of field-induced fragmentation of nickel clusters using Scanning Tunneling Microscopy, M.V.H. Rao, V. Srinivas, V.V. Rao, B.K. Mathur and K.L. Chopra Schottky barrier Cadmium selenide-amorphous hydrogen-ated slid on oxidate on Ethologous disconvious in Chemistry at silicon crystalline surfaces, G.F. Cerofolini and L. Meda Silicon carbide The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, Ch. Bram, PR. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Müller Schottky barrier Schottky barrier Capacitance-voltage characteristics of Schottky barrier diode in the presence of deep-level impurities and series resistance, P. Chattopadhyay and S. Sanyal Secondary ion mass spectrometry SIMS microprofiles of Pb-5%Sn solder joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs*-SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth Capacitance-voltage characteristics of Schottky barrier diode in the presence of deep-level impurities and series resistance, P. Chattopadhyay and S. Sanyal Silver Characterization of thin Ag films deposited onto InP(001)-p(2×4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita The effect of anodic polarization on a Ag	
composition and structure, U. Starke, Ch. Bram, PR. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Miller Characterization of triplex RNA poly[rU]- poly[rA]- poly[rU] adsorbed on silver colloids by Fourier transform surface enhanced Raman scattering and scan- ning tunneling microscopy, Y. Fang, C. Bai, T. Wang and YQ. Tang Observation of field-induced fragmentation of nickel clusters using Scanning Tun- neling Microscopy, M.V.H. Rao, V. Srinivas, V.V. Rao, B.K. Mathur and K.L. Chopra Schottky barrier Capacitance-voltage characteristics of Schottky barrier diode in the presence of deep-level impurities and series resis- tance, P. Chattopadhyay and S. Sanyal Secondary ion mass spectrometry SIMS microprofiles of Pb-5%Sn solder joints in electronic devices after acceler- ated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs*-SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth The (0001)-pug silicon crystalline surfaces, G.F. Cerofolini, G. La Bruna and L. Meda 89 (1995) 331 The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, Ch. Bram, PR. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Müller 89 (1995) 417 Silicon oxide Plasma-enhanced reactively evaporated de- position of SiO ₂ films, A.A. Shklyaev and A.S. Medvedev A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a ¹⁵³ Cs* beam, H. Tomizuka and A. Ayame 89 (1995) 1 Characterization of thin Ag films deposited onto InP(001)-p(2 ×4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita The effect of anodic polarization on a Ag	(1995) 281
Characterization of triplex RNA poly[rU] - poly[rA] - p	(1995) 289
colloids by Fourier transform surface enhanced Raman scattering and scanning tunneling microscopy, Y. Fang, C. Bai, T. Wang and YQ. Tang Observation of field-induced fragmentation of nickel clusters using Scanning Tunneling Microscopy, M.V.H. Rao, V. Srinivas, V.V. Rao, B.K. Mathur and K.L. Chopra Schottky barrier Schottky barrier Capacitance-voltage characteristics of Schottky barrier diode in the presence of deep-level impurities and series resistance, P. Chattopadhyay and S. Sanyal Secondary ion mass spectrometry SIMS microprofiles of Pb-5%Sn solder joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs*-SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a life to the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs*-SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a life to the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs*-SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth Time effect of anodic polarization on a Ag argaphical analysis of transient response curves at an early stage in SIMS depth Time effect of anodic polarization on a Ag argaphical analysis of transient response curves at an early stage in SIMS depth Time effect of anodic polarization on a Ag argaphical analysis of transient response curves at an early stage in SIMS depth Time effect of anodic polarization on a Ag argaphical analysis of transient response curves at an early stage in SIMS depth Time effect of anodic polarization on a Ag argaphical analysis of transient response curves at an early stage in SIMS depth Time effect of anodic polarization on a Ag argaphical analysis of transient response curves at an early stage in SIMS depth	(1995) 351
Bai, T. Wang and YQ. Tang Observation of field-induced fragmentation of nickel clusters using Scanning Tunneling Microscopy, M.V.H. Rao, V. Srinivas, V.V. Rao, B.K. Mathur and K.L. Chopra Schottky barrier Capacitance-voltage characteristics of Schottky barrier diode in the presence of deep-level impurities and series resistance, P. Chattopadhyay and S. Sanyal Secondary ion mass spectrometry SIMS microprofiles of Pb-5%Sn solder joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs ⁺ -SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth A graphical analysis of transient response curves at an early stage in SIMS depth Tomizuka and A. Ayame 89 (1995) 169 The (0001)-surface of 6H-SiC: morphology, composition and structure, U. Starke, Ch. Bram, PR. Steiner, W. Hartner, L. Hammer, K. Heinz and K. Müller 89 (1995) 417 Silicon oxide Plasma-enhanced reactively evaporated deposition of SiO ₂ films, A.A. Shklyaev and A.S. Medvedev and A.S. Medvedev and A.S. Medvedev 38 (1995) 205 A graphical analysis of transient response curves at an early stage in SIMS depth Tomizuka and A. Ayame 89 (1995) 1 Characterization of thin Ag films deposited onto InP(001)-p(2 × 4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita The effect of anodic polarization on a Ag	(1995) 361
of nickel clusters using Scanning Tunneling Microscopy, M.V.H. Rao, V. Srinivas, V.V. Rao, B.K. Mathur and K.L. Chopra Schottky barrier Capacitance-voltage characteristics of Schottky barrier diode in the presence of deep-level impurities and series resistance, P. Chattopadhyay and S. Sanyal Secondary ion mass spectrometry SIMS microprofiles of Pb-5%Sn solder joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs ⁺ -SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth years of LEED, RES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita The effect of anodic polarization on a Ag	
Schottky barrier Capacitance-voltage characteristics of Schottky barrier diode in the presence of deep-level impurities and series resistance, P. Chattopadhyay and S. Sanyal Secondary ion mass spectrometry SIMS microprofiles of Pb-5%Sn solder joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs*-SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a 133 Cs+ beam, H. Tomizuka and A. Ayame Silver Silver Characterization of thin Ag films deposited onto InP(001)-p(2 × 4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a 133 Cs+ beam, H. Tomizuka and A. Ayame Silver Silver Characterization of thin Ag films deposited onto InP(001)-p(2 × 4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita The effect of anodic polarization on a Ag	(1005) 175
Capacitance-voltage characteristics of Schottky barrier diode in the presence of deep-level impurities and series resistance, P. Chattopadhyay and S. Sanyal 89 (1995) 205 Secondary ion mass spectrometry SIMS microprofiles of Pb-5%Sn solder joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi 89 (1995) 1 A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs*-SIMS technique, X. Chen and Y. Wang 89 (1995) 169 A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a 133 Cs+ beam, H. Tomizuka and A. Ayame 89 (1995) 1 Characterization of thin Ag films deposited onto InP(001)-p(2 × 4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita 89 (1995) 169 A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a 133 Cs+ beam, H. Tomizuka and A. Ayame 89 (1995) 1 Characterization of thin Ag films deposited onto InP(001)-p(2 × 4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita 7 The effect of anodic polarization on a Ag	(1995) 175
Schottky barrier diode in the presence of deep-level impurities and series resistance, P. Chattopadhyay and S. Sanyal Secondary ion mass spectrometry SIMS microprofiles of Pb-5%Sn solder joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs*-SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a 133 Cs* beam, H. Tomizuka and A. Ayame 89 (1995) 1 Characterization of thin Ag films deposited onto InP(001)-p(2 × 4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita A graphical analysis of transient response curves at an early stage in SIMS depth The effect of anodic polarization on a Ag	
tance, P. Chattopadhyay and S. Sanyal 89 (1995) 205 A graphical analysis of transient response curves at an early stage in SIMS depth profiling using a ¹³³ Cs ⁺ beam, H. Tomizuka and A. Ayame 89 (1995) 1 SIMS microprofiles of Pb-5%Sn solder joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs ⁺ -SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth 89 (1995) 109 Characterization of thin Ag films deposited onto InP(001)-p(2 × 4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita 89 (1995) 169 The effect of anodic polarization on a Ag	(1995) 49
SIMS microprofiles of Pb-5%Sn solder joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs ⁺ -SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth Tomizuka and A. Ayame 89 (1995) 1 Characterization of thin Ag films deposited onto InP(001)-p(2 × 4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita The effect of anodic polarization on a Ag	
joints in electronic devices after accelerated life tests, A. Scandurra, A. Porto and O. Puglisi A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs ⁺ -SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth Silver Characterization of thin Ag films deposited onto InP(001)-p(2 × 4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita 89 (1995) 169 RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita The effect of anodic polarization on a Ag	(1995) 281
A study of the composition distribution at the Ti/Al ₂ O ₃ interface using the MCs ⁺ -SIMS technique, X. Chen and Y. Wang A graphical analysis of transient response curves at an early stage in SIMS depth A study of the composition distribution at the provided onto InP(001)-p(2 × 4) surface at room temperature by means of LEED, RHEED, AES and RBS-channeling techniques, M. Hanebuchi, T. Katoh and K. Morita 89 (1995) 169 K. Morita The effect of anodic polarization on a Ag	
Wang 89 (1995) 169 techniques, M. Hanebuchi, T. Katoh and K. Morita 89 (1995) 169 techniques at an early stage in SIMS depth The effect of anodic polarization on a Ag	
1330 + 1	(1995) 113
Tomizuka and A. Ayame 89 (1995) 281 trolyte, J.K. Hong, IH. Oh, SA. Hong	(1995) 229
Silicides Interaction of oxygen and silver on the V(100) surface, T. Valla, P. Pervan and	
	(1995) 375

emission, U. Kürpick, G. Meister and A. Goldmann	89 (1995) 383	num nitride films, H.J. Lee, JG. Choi, C.W. Colling, M.S. Mudholkar and L.T.	
		Thompson	89 (1995) 121
Sulphur dioxide		Thermal effects on structural characteriza-	
		tion of evaporated CdTe films during	
A new parameter to characterize limestones		and after deposition, A. Ashour, M.R. Ebeid, N. El-Kadry, M.F. Ahmed and	
as SO ₂ sorbents, M.J. Muñoz-Guillena,		A.A. Ramadan	89 (1995) 159
A. Linares-Solano and C. Salinas-		Preparation of a model Ziegler-Natta cata-	05 (1553) 135
Martínez de Lecea	89 (1995) 197	lyst. Surface science studies of magne-	
		sium chloride thin film deposited on	
Tantalum		gold and its interaction with titanium	
1 umuum		chloride, E. Magni and G.A. Somorjai	89 (1995) 187
		Quantitative correction of backscattering in	(
Tantalum oxide film formation by excimer		Auger electron spectroscopy of thin	
laser ablation, Y. Nishimura, H. Ujita	()	films, G. Lévêque and J. Bonnet	89 (1995) 211
and M. Tsuji	89 (1995) 393	Dependence of electromigration rate on ap-	,
A photoelectron study of the oxidation of		plied electric potential, B.H. Jo and R.W.	
Ta(110) and thin aluminum layers on		Vook	89 (1995) 237
Ta(110), M.W. Ruckman, SL. Qiu and	00 (1005) 101	XPS investigations of the interactions of	
M. Strongin	89 (1995) 401	hydrogen with thin films of zirconium	
		oxide. I. Hydrogen treatments on a 10 Å	
Thermal desorption		thick film, P.C. Wong, Y.S. Li, M.Y.	
		Zhou and K.A.R. Mitchell	89 (1995) 255
The distribution of activation energy for		XPS investigations of the interactions of	
hydrogen desorption over silica-sup-		hydrogen with thin films of zirconium	
ported nickel catalysts determined from		oxide. II. Effects of heating a 26 Å thick	
temperature-programmed desorption		film after treatment with a hydrogen	
spectra, M. Arai, Y. Nishiyama, T. Ma-		plasma, Y.S. Li, P.C. Wong and K.A.R.	
suda and K. Hashimoto	89 (1995) 11	Mitchell	89 (1995) 263
Thermal desorption spectroscopy study of		Cadmium selenide-amorphous hydrogen-	
chemically etched porous silicon, N.		ated silicon heterostructures, S. Wu and	
Hadj Zoubir and M. Vergnat	89 (1995) 35	D. Haneman	89 (1995) 289
Reactions of CO and NO on Mg promoted		Interfacial reaction of NiO with Al ₂ O ₃	
cobalt, T. Vaara, J. Lahtinen and P.		(11 $\overline{2}$ 0) and polycrystalline α -Al ₂ O ₃ ,	
Hautojärvi	89 (1995) 103	P.H. Bolt, S.F. Lobner, J.W. Geus and	00 (1005) 000
Temperature-programmed desorption and		F.H.P.M. Habraken	89 (1995) 339
decomposition of NH3 over molybde-		Interaction of oxygen and silver on the	
num nitride films, H.J. Lee, JG. Choi,		V(100) surface, T. Valla, P. Pervan and	00 (1005) 275
C.W. Colling, M.S. Mudholkar and L.T.		M. Milun	89 (1995) 375
Thompson	89 (1995) 121	Tantalum oxide film formation by excimer laser ablation, Y. Nishimura, H. Ujita	
Oxygen exchange between adsorbed NO and	()	and M. Tsuji	89 (1995) 393
MgO surfaces, Y. Yanagisawa	89 (1995) 251	and w. Isuji	07 (1775) 373
Thin films		Tin	
		SIMS microprofiles of Pb-5%Sn solder	
Plasma-enhanced reactively evaporated de-		joints in electronic devices after acceler-	
position of SiO ₂ films, A.A. Shklyaev		ated life tests, A. Scandurra, A. Porto	
and A.S. Medvedev	89 (1995) 49	and O. Puglisi	89 (1995) 1
Characterization of thin Ag films deposited		wild O. I ugitor	02 (1993) 1
onto $InP(001)-p(2 \times 4)$ surface at room		Tr.	
temperature by means of LEED,		Titanium	
RHEED, AES and RBS-channeling			
techniques, M. Hanebuchi, T. Katoh and	00 (4005) 445	A study of the composition distribution at	
K. Morita	89 (1995) 113	the Ti/Al ₂ O ₃ interface using the	
Temperature-programmed desorption and		MCs ⁺ -SIMS technique, X. Chen and Y.	90 (1005) 160
decomposition of NH3 over molybde-		Wang	89 (1995) 169

Preparation of a model Ziegler-Natta cata- lyst. Surface science studies of magne- sium chloride thin film deposited on gold and its interaction with titanium		Activation treatments and surface study of amorphous Fe ₉₀ Zr ₁₀ and Fe _{87.8} Zr ₁₀ Co ₂ Al _{0.2} catalysts, X.K. Wang, N.F. Shen, Z.S. Yang and H.C. Gu	89 (1995) 297
chloride, E. Magni and G.A. Somorjai Titanium oxide	89 (1995) 187	Deposition by laser ablation and characteri- zation of titanium dioxide films on polyethylene-terephthalate, N. Lobstein,	
		E. Millon, A. Hachimi, J.F. Muller, M.	90 (1005) 207
Deposition by laser ablation and characterization of titanium dioxide films on polyethylene-terephthalate, N. Lobstein, E. Millon, A. Hachimi, J.F. Muller, M. Alnot and J.J. Ehrhardt	89 (1995) 307	Alnot and J.J. Ehrhardt Interfacial reaction of NiO with Al ₂ O ₃ (1120) and polycrystalline α-Al ₂ O ₃ , P.H. Bolt, S.F. Lobner, J.W. Geus and F.H.P.M. Habraken	89 (1995) 307 89 (1995) 339
The chemical interaction between plasma- excited nitrogen and the surface of tita-		Yttrium	
nium dioxide, S. Kameoka, T. Kuriyama, M. Kuroda, S. Ito and K. Kunimori	89 (1995) 411	Ultraviolet inverse photoemission study of	
Tungsten		the oxidation of YFe ₂ , P. Vavassori, L. Callegaro and E. Puppin The effect of anodic polarization on a Ag	89 (1995) 93
M-S (M = Mo, W) cluster compound films on copper surfaces, X.R. Ye, H.W. Hou, X.Q. Xin and C.F. Hammer	89 (1995) 151	electrode deposited on YSZ solid electrolyte, J.K. Hong, IH. Oh, SA. Hong and W.Y. Lee	89 (1995) 229
Vanadium		Zirconium	
Interaction of oxygen and silver on the V(100) surface, T. Valla, P. Pervan and M. Milun	89 (1995) 375	The effect of anodic polarization on a Ag electrode deposited on YSZ solid elec- trolyte, J.K. Hong, IH. Oh, SA. Hong and W.Y. Lee	89 (1995) 229
Water		XPS investigations of the interactions of hydrogen with thin films of zirconium	69 (1993) 229
Surface reactions on palladium hydride in vacuum, air and water studied in situ with mass spectrometry, L. Gråsjö, G. Hultquist, K.L. Tan and M. Seo	89 (1995) 21	oxide. I. Hydrogen treatments on a 10 Å thick film, P.C. Wong, Y.S. Li, M.Y. Zhou and K.A.R. Mitchell XPS investigations of the interactions of hydrogen with thin films of zirconium	89 (1995) 255
X-ray diffraction		oxide. II. Effects of heating a 26 Å thick film after treatment with a hydrogen plasma, Y.S. Li, P.C. Wong and K.A.R.	
Thermal effects on structural characteriza- tion of evaporated CdTe films during and after deposition, A. Ashour, M.R. Ebeid, N. El-Kadry, M.F. Ahmed and A.A. Ramadan	89 (1995) 159	Mitchell Activation treatments and surface study of amorphous Fe ₉₀ Zr ₁₀ and Fe _{87.8} Zr ₁₀ Co ₂ Al _{0.2} catalysts, X.K. Wang, N.F. Shen, Z.S. Yang and H.C. Gu	89 (1995) 263 89 (1995) 297
	07 (4770) 407	and the transfer	02 (1220) 421

